

# RSEG-2006

## RELIABILITY DATA

DWG.No.SC-575-RSEG-2006-001			
QA	R & D		
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The following data are typical values. As all units have nearly the same characteristics, the data to be considered as ability values.

## 1. Calculated Values of MTBF

MODEL : RSEG-2006

## (1) Calculating Method

Calculated Based on parts stress Reliability projection of MIL-HDBK-217F NOTICE2.

Individual failure rates  $\lambda_G$  is given to each part and MTBF is Calculated by the count of each part.

$$MTBF = \frac{1}{\lambda_{equip}} = \frac{1}{\sum_{i=1}^n N_i (\lambda_G \pi_Q)_i} \times 10^6 \text{ (hours)}$$

$\lambda_{equip}$  : Total equipment failure rate (Failure / 106 Hours)

$\lambda_G$  : Generic failure rate for the i th generic part (Failure/ 106 Hours)

$N_i$  : Quantity of i th generic part

$N$  : Number of different generic part categories

$\pi_Q$  : Generic quality factor for the i th generic part ( $\pi_Q=1$ )

## (2) MTBF Values

GF : Ground, Fixed

$$MTBF = \underline{\underline{13,583,265 \text{ (Hours)}}}$$

**RSEG-2006****2. Vibration Test**

MODEL: RSEG-2006

**(1) Vibration Test Class**

Frequency Variable Endurance Test

**(2) Equipment Used**

Controller VS-1000-6, Vibrator 905-FN (IMV CORP.)

**(3) The Number of D.U.T (Device Under Test)**

6 units

**(4) Test Conditions**

Frequency : 10~55Hz

Amplitude : 1.5mm, Sweep for 1 min.

Dimension and times : X, Y and Z Directions for 2 hours each.

**(5) The Method**

Fix the D.U.T on the fitting-stage

**(6) Test Results**

PASS

**Typical Sample Data**

Check item	Spec.		Before Test	After Test
Attenuation(dB)	Differential Mode : 25dB min.	1.5 MHz	41.32	40.97
		30 MHz	52.68	52.63
	Common Mode: 25dB min.	1 MHz	34.18	34.28
		20 MHz	35.14	35.40
Leakage Current (mA)	0.75mA max. (250V, 60Hz)	Line1	0.47	0.47
		Line2	0.47	0.47
DC Resistance (mΩ)	100 mΩ max.		0.51	0.51
Test Voltage	L-L : 1768Vdc 60sec.		OK	OK
	L-E : 1500Vdc 60sec.			
Isolation Resistance(MΩ)	100 MΩ min.(500Vdc 60sec.)		2.16×E5	2.25×E5

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3. Heat Cycle Test

MODEL: RSEG-2006

(1)Equipment Used

TEMPERATURE CHAMBER TSA-71H-W (ESPEC CORP.)

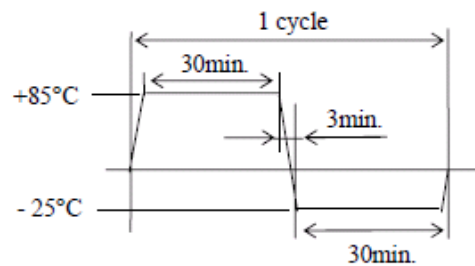
(2)The Number of D.U.T (Device Under Test)

6 units

(3)Test Conditions

Ambient Temperature : -25~+85°C

Test Cycles: 100 cycles



(4)The Method

Before the test check if there is no abnormal characteristics and put the D.U.T in the testing chamber. Then test it in the above cycles, After the test is completed leave it for 1 hour at room temperature and check it if there is no abnormal each characteristics.

(5)Test Results

PASS

Typical Sample Data

Check item	Spec.		Before Test	After Test
Attenuation(dB)	Differential Mode : 25dB min.	1.5 MHz	41.43	41.14
		30 MHz	56.11	56.07
	Common Mode: 25dB min.	1MHz	34.23	34.33
		20 MHz	35.55	35.44
Leakage Current (mA)	0.75mA max. (250V, 60Hz)	Line1	0.45	0.45
		Line2	0.45	0.45
DC Resistance (mΩ)	100 mΩ max.		0.48	0.50
Test Voltage	L-L : 1768Vdc 60sec. L-E : 1500Vdc 60sec.		OK	OK
Isolation Resistance(MΩ)	100 MΩ min.(500Vdc 60sec.)		3.56×E5	3.51×E5

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## 4. Humidity Test

MODEL: RSEG-2006

## (1)Equipment Used

TEMP. &amp; HUMID. CHAMBER PR-4KT (ESPEC CORP.)

## (2)The Number of D.U.T (Device Under Test)

6 units

## (3)Test Conditions

Ambient Temperature : +40°C

Test Times: 500 hours

Ambient Humidity: 90~95%RH No Dewdrop

## (4)The Method

Before the test check if there is no abnormal characteristics and put the D.U.T in the testing chamber. Then test it in the above conditions. After the test is completed leave it for 1 hour at room temperature and check it if there is no abnormal each characteristics.

## (5)Test Results

PASS

## Typical Sample Data

Check item	Spec.		Before Test	After Test
Attenuation(dB)	Differential Mode : 25dB min.	1.5 MHz	40.01	39.87
		30MHz	56.57	56.34
	Common Mode: 25dB min.	1MHz	31.93	31.94
		20 MHz	35.37	35.38
Leakage Current (mA)	0.75mA max. (250V, 60Hz)	Line1	0.47	0.47
		Line2	0.47	0.47
DC Resistance (mΩ)	100mΩ max.		0.51	0.51
Test Voltage	L-L : 1768Vdc 60sec.		OK	OK
	L-E : 1500Vdc 60sec.			
Isolation Resistance(MΩ)	100 MΩ min.(500Vdc 60sec.)		1.96×E5	2.06×E5

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## 5. High Temperature Resistance Test

MODEL: RSEG-2006

## (1)Equipment Used

TEMPERATURE CHAMBER PHH-300 (ESPEC CORP.)

## (2)The Number of D.U.T (Device Under Test)

6 units

## (3)Test Conditions

Ambient Temperature : +55°C

Test Times: 500 hours

Operating: DC 6A

## (4)The Method

Before the test check if there is no abnormal characteristics and put the D.U.T in the testing chamber. Then test it in the above conditions. After the test is completed leave it for 1 hour at room temperature and check it if there is no abnormal each characteristics.

## (5)Test Results

PASS

## Typical Sample Data

Check item	Spec.		Before Test	After Test
Attenuation(dB)	Differential Mode : 25dB min.	1.5 MHz	40.34	40.00
		30 MHz	58.03	57.82
	Common Mode: 25dB min.	1MHz	33..98	34.03
		20 MHz	35.37	35.13
Leakage Current (mA)	0.75mA max. (250V, 60Hz)	Line1	0.48	0.48
		Line2	0.47	0.47
DC Resistance (mΩ)	100mΩ max.		0.51	0.51
Test Voltage	L-L : 1768Vdc 60sec.		OK	OK
	L-E : 1500Vdc 60sec.			
Isolation Resistance(MΩ)	100 MΩ min.(500Vdc 60sec.)		2.30×E5	2.43×E5

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## 6. Low Temperature Storage Test

MODEL: RSEG-2006

## (1)Equipment Used

TEMPERATURE CHAMBER PG-2FT (ESPEC CORP.)

## (2)The Number of D.U.T (Device Under Test)

6 units

## (3)Test Conditions

Ambient Temperature :  $-25^{\circ}\text{C}$ 

Test Times: 500 hours

## (4)The Method

Before the test check if there is no abnormal characteristics and put the D.U.T in the testing chamber. Then test it in the above conditions. After the test is completed leave it for 1 hour at room temperature and check it if there is no abnormal each characteristics.

## (5)Test Results

PASS

## Typical Sample Data

Check item	Spec.		Before Test	After Test
Attenuation(dB)	Differential Mode : 25dB min.	1.5 MHz	40.58	40.21
		30 MHz	58.87	58.95
	Common Mode: 25dB min.	1MHz	34.26	34.36
		20 MHz	35.22	35.24
Leakage Current (mA)	0.75mA max. (250V, 60Hz)	Line1	0.47	0.48
		Line2	0.47	0.47
DC Resistance (m $\Omega$ )	100m $\Omega$ max.		0.51	0.51
Test Voltage	L-L : 1768Vdc 60sec.		OK	OK
	L-E : 1500Vdc 60sec.			
Isolation Resistance(M $\Omega$ )	100 M $\Omega$ min.(500Vdc 60sec.)		1.91 $\times$ E5	1.87 $\times$ E5